

Search Notes

Application/Control No.

10/698,325

Examiner

Hai C. Pham

Applicant(s)/Patent under
Reexamination

REIHL, HEINER

Art Unit

2861

SEARCHED

Class	Subclass	Date	Examiner
347	132-133, 136-237, 246-247	11/12/2005	HP
	140		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
347	236, 246	11/12/2005	HP
PGPub. Text Search		11/12/2005	HP

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST Text Search	11/12/2005	HP